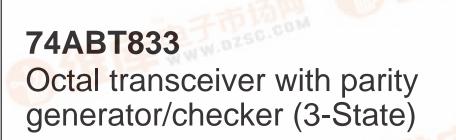
## INTEGRATED CIRCUITS\*CB打样工厂, 24小时力



DATA SHEET

Product specification IC23 Data Handbook 1993 Jun 21







## 74ABT833

#### **FEATURES**

- Low static and dynamic power dissipation with high speed and high output drive
- Open-collector ERROR output with flag register
- Output capability: +64mA/–32mA
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Power up/down 3-State
- Live insertion/extraction permitted

#### DESCRIPTION

The 74ABT833 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

#### QUICK REFERENCE DATA

The 74ABT833 is an octal transceiver with a parity generator/checker and is intended for bus-oriented applications.

When Output Enable A ( $\overline{OEA}$ ) is High, it will place the A outputs in a high impedance state. Output Enable B ( $\overline{OEB}$ ) controls the B outputs in the same way.

The parity generator creates an odd parity output (PARITY) when  $\overline{OEB}$  is Low. When  $\overline{OEA}$  is Low, the parity of the B port, including the PARITY input, is checked for odd parity. When an error is detected, the error data is sent to the input of a storage register. If a Low-to-High transition happens at the clock input (CP), the error data is stored in the register and the Open-collector error flag (ERROR) will go Low. The error flag register is cleared with a Low pulse on the CLEAR input.

If both  $\overline{\text{OEA}}$  and  $\overline{\text{OEB}}$  are Low, data will flow from the A bus to the B bus and the part is forced into an error condition which creates an inverted PARITY output. This error condition can be used by the designer for system diagnostics.

SYMBOL	PARAMETER	CONDITIONS T <sub>amb</sub> = 25°C; GND = 0V	TYPICAL	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay An to Bn or Bn to An	C <sub>L</sub> = 50pF; V <sub>CC</sub> = 5V	3.4	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay An to PARITY	$C_L = 50 pF; V_{CC} = 5V$	7.4	ns
C <sub>IN</sub>	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	4	pF
C <sub>I/O</sub>	I/O capacitance	Outputs disabled; $V_O = 0V$ or $V_{CC}$	7	pF
I <sub>CCZ</sub>	Total supply current	Outputs disabled; V <sub>CC</sub> =5.5V	50	μΑ

#### **ORDERING INFORMATION**

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
24-Pin Plastic DIP	-40°C to +85°C	74ABT833 N	74ABT833 N	SOT222-1
24-Pin plastic SO	–40°C to +85°C	74ABT833 D	74ABT833 D	SOT137-1
24-Pin Plastic SSOP Type II	-40°C to +85°C	74ABT833 DB	74ABT833 DB	SOT340-1
24-Pin Plastic TSSOP Type I	–40°C to +85°C	74ABT833 PW	74ABT833PW DH	SOT355-1

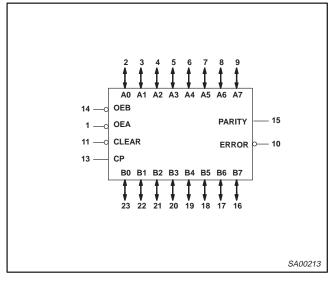
#### **PIN CONFIGURATION**

OEA 1	-	24 VCC	
A0 2		23 B0	
A1 3		22 B1	
A2 4		21 B2	
A3 5		20 B3	
A4 6	-	19 B4	
A5 7		18 B5	
A6 8	-	17 B6	
A7 9	-	16 B7	
ERROR 10	-	15 PARITY	
CLEAR 11	-	14 OEB	
GND 12	-	13 CP	
	TOP VIEW		SA00212

#### **PIN DESCRIPTION**

SYMBOL	PIN NUMBER	NAME AND FUNCTION
A0 – A7	2, 3, 4, 5, 6, 7, 8, 9	A port 3-State inputs/outputs
B0 – B7	23, 22, 21, 20, 19, 18, 17, 16	B port 3-State inputs/outputs
OEA	1	Enables the A outputs when Low
OEB	14	Enables the B outputs when Low
PARITY	15	Parity output/input
ERROR	10	Error output (open collector)
CLEAR	11	Clears the error flag register when Low
CP	13	Clock input
GND	12	Ground (0V)
V <sub>CC</sub>	24	Positive supply voltage

#### LOGIC SYMBOL



#### **FUNCTION TABLE**

	INPUTS				OUTPUTS			
MODE	OEB	OEA	An $\Sigma$ of Highs	Bn + Parity $\Sigma$ of Highs	An	Bn	PARITY	
A data to B bus and generate odd parity output	L	Н	Odd Even	(output)	(input)	An	L H	
B data to A bus and check for parity error <sup>1</sup>	Н	L	(output)	Х	Bn	(input)	(input)	
A bus and B bus disabled <sup>2</sup>	Н	Н	Х	Х	Z	Z	Z	
A data to B bus and generate inverted parity output	L	L	Odd Even	(output)	(input)	An	H L	

#### NOTES:

1. Error checking is detailed in the Error Flag Function Table below.

2. When clocked, the error output is Low if the sum of A inputs is even or High if the sum of A inputs is odd.

#### **ERROR FLAG FUNCTION TABLE**

		INPUT	S	Internal node	Output	
MODE	CLEAR	СР	Bn + Parity Σ of Highs	Point "P"	Pre-state ERRORn-1	ERROR OUTPUT
Sample	H H H	↑ ↑ X	Odd Even X	H L X	H X L	H L L
Hold	Н	¢	Х	Х	Х	NC
Clear	L	Х	Х	Х	Х	Н

Н High voltage level steady state =

Low voltage level steady state =

L X = Don't care

NC = No change Z = High imped  $\uparrow = Low-to-High$ = High impedance "off" state

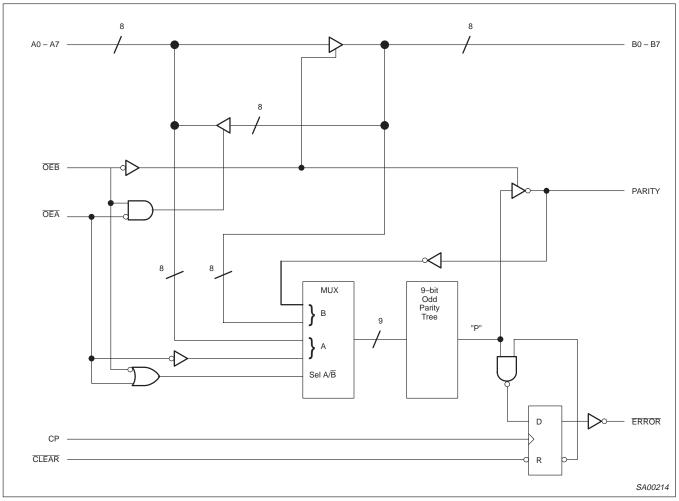
Low-to-High clock transition =

Ţ = Not a Low-to-High clock transition

## 74ABT833

74ABT833

#### LOGIC DIAGRAM



#### **ABSOLUTE MAXIMUM RATINGS<sup>1, 2</sup>**

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V <sub>CC</sub>	DC supply voltage		-0.5 to +7.0	V
I <sub>IK</sub>	DC input diode current	V <sub>1</sub> < 0	-18	mA
VI	DC input voltage <sup>3</sup>		-1.2 to +7.0	V
I <sub>OK</sub>	DC output diode current	V <sub>O</sub> < 0	-50	mA
V <sub>OUT</sub>	DC output voltage <sup>3</sup>	output in Off or High state	-0.5 to +5.5	V
I <sub>OUT</sub>	DC output current	output in Low state	128	mA
T <sub>stg</sub>	Storage temperature range		-65 to 150	°C

NOTES:

Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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#### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIM	ITS	UNIT
		Min	Max	]
V <sub>CC</sub>	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V <sub>CC</sub>	V
V <sub>IH</sub>	High-level input voltage	2.0		V
V <sub>IL</sub>	Low-level input voltage		0.8	V
V <sub>OH</sub>	High-level output voltage, ERROR		5.5	V
I <sub>OH</sub>	High-level output current		-32	mA
I <sub>OL</sub>	Low-level output current		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	5	ns/V
T <sub>amb</sub>	Operating free-air temperature range	-40	+85	°C

#### **DC ELECTRICAL CHARACTERISTICS**

						LIMITS			
SYMBOL	PARAMETER		TEST CONDITIONS		<sub>mb</sub> = +25	°C	T <sub>amb</sub> = to +	-40°C 85°C	UNIT
				Min	Тур	Max	Min	Max	
V <sub>IK</sub>	Input clamp volt	age	V <sub>CC</sub> = 4.5V; I <sub>IK</sub> = -18mA		-0.9	-1.2		-1.2	V
I <sub>OH</sub>	High-level output ERROR ONLY	ut current	$V_{CC}$ = 5.5V; $V_{OH}$ = 5.5V; $V_{I}$ = $V_{IL}$ or $V_{IH}$			20		20	μA
			$V_{CC}$ = 4.5V; $I_{OH}$ = -3mA; $V_I$ = $V_{IL}$ or $V_{IH}$	2.5	3.5		2.5		V
V <sub>OH</sub>	High-level output voltage All outputs except ERROR		$V_{CC}$ = 5.0V; $I_{OH}$ = -3mA; $V_I$ = $V_{IL}$ or $V_{IH}$	3.0	4.0		3.0		V
			$V_{CC}$ = 4.5V; $I_{OH}$ = -32mA; $V_{I}$ = $V_{IL}$ or $V_{IH}$	2.0	2.6		2.0		V
V <sub>OL</sub>	Low-level output	it voltage	$V_{CC}$ = 4.5V; $I_{OL}$ = 64mA; $V_I$ = $V_{IL}$ or $V_{IH}$		0.42	0.55		0.55	V
I <sub>I</sub>	Input leakage	Control pins	$V_{CC} = 5.5V; V_{I} = GND \text{ or } 5.5V$		±0.01	±1.0		±1.0	μΑ
	current	Data pins	$V_{CC} = 5.5V; V_I = GND \text{ or } 5.5V$		±5	±100		±100	μΑ
I <sub>OFF</sub>	Power-off leaka	ge current	$V_{CC}$ = 0.0V; $V_{I}$ or $V_{O} \leq 4.5 V$		±5.0	±100		±100	V
I <sub>PU</sub> I <sub>PD</sub>	Power-up/down output current <sup>3</sup>	3-State	$V_{CC}$ = 2.0V; or V <sub>O</sub> = 0.5V; V <sub>I</sub> = GND or V <sub>CC</sub> ; V <sub>OE</sub> = Don't care		±5.0	±50		±50	V
I <sub>IH</sub> + I <sub>OZH</sub>	3-State output H	ligh current	$V_{CC}$ = 5.5V; $V_{O}$ = 2.7V; $V_{I}$ = $V_{IL}$ or $V_{IH}$		5.0	50		50	μA
I <sub>IL</sub> + I <sub>OZL</sub>	3-State output L	ow current	$V_{CC}$ = 5.5V; $V_{O}$ = 0.5V; $V_{I}$ = $V_{IL}$ or $V_{IH}$		-5.0	-50		-50	μA
I <sub>CEX</sub>	Output High lea	kage current	$V_{CC}$ = 5.5V; $V_{O}$ = 5.5V; $V_{I}$ = GND or $V_{CC}$		5.0	50		50	μA
Ι <sub>Ο</sub>	Output current <sup>1</sup>		V <sub>CC</sub> = 5.5V; V <sub>O</sub> = 2.5V	-50	-80	-180	-50	-180	mA
I <sub>CCH</sub>			$V_{CC}$ = 5.5V; Outputs High, $V_{I}$ = GND or $V_{CC}$		50	250		250	μA
I <sub>CCL</sub>	Quiescent supp	ly current	$V_{CC}$ = 5.5V; Outputs Low, $V_I$ = GND or $V_{CC}$		20	30		30	mA
I <sub>CCZ</sub>	1		$V_{CC}$ = 5.5V; Outputs 3-State; V <sub>I</sub> = GND or V <sub>CC</sub>		50	250		250	μΑ
$\Delta I_{CC}$	Additional supp input pin <sup>2</sup>	ly current per	$V_{CC}$ = 5.5V; one input at 3.4V, other inputs at $V_{CC}$ or GND		0.3	1.5		1.5	mA

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

This is the increase in supply current for each input at 3.4V.
This parameter is valid for any V<sub>CC</sub> between 0V and 2.1, with a transition time of up to 10msec. From V<sub>CC</sub> = 2.1V to V<sub>CC</sub> = 5V ± 10%, a transition of up to 100µsec is permitted. The ERROR output pin 10 is not included in this spec due to the open collector design.

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#### **AC CHARACTERISTICS**

GND = 0V;  $t_R = t_F$  = 2.5ns;  $C_L$  = 50pF,  $R_L$  = 500 $\Omega$ 

			LIMITS					
SYMBOL	PARAMETER	WAVEFORMS	T <sub>amb</sub> = +25°C V <sub>CC</sub> = +5.0V			T <sub>amb</sub> = -4 V <sub>CC</sub> = +5	UNIT	
			Min	Тур	Max	Min	Max	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay An to Bn or Bn to An	2	1.2 1.0	3.4 2.6	4.8 4.0	1.2 1.0	5.3 4.5	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay An to PARITY	1 2	2.1 2.5	7.4 7.4	9.5 9.7	2.1 2.5	11.2 11.0	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay OEA to PARITY	1 2	2.6 3.1	6.6 6.7	8.5 8.6	2.6 3.1	10.5 10.0	ns
t <sub>PLH</sub>	Propagation delay CLEAR to ERROR	5	1.0	2.9	4.4	1.0	5.2	ns
t <sub>PHL</sub>	Propagation delay CP to ERROR	1	2.5	4.2	5.7	2.5	6.2	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time OEA to An or OEB to Bn, PARITY	3 4	1.0 2.1	3.2 4.1	5.1 5.8	1.0 2.1	6.2 6.7	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time OEA to An or OEB to Bn, PARITY	3 4	3.1 3.2	5.1 5.6	7.3 7.7	3.1 3.2	7.9 8.1	ns

#### AC SETUP REQUIREMENTS

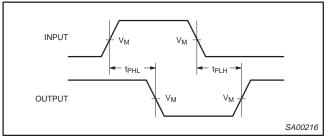
GND = 0V;  $t_R = t_F$  = 2.5ns;  $C_L$  = 50pF,  $R_L$  = 500 $\Omega$ 

			LIMITS			
SYMBOL	PARAMETER	WAVEFORMS	T <sub>amb</sub> = +25°C V <sub>CC</sub> = +5.0V		T <sub>amb</sub> = −40 to +85°C V <sub>CC</sub> = +5.0V ±10%	UNIT
			Min	Тур	Min	
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time, High or Low Bn or PARITY to CP	6	9.8 8.1	6.9 4.0	9.8 8.1	ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, High or Low Bn or PARITY to CP	6	0.0 0.0	-3.7 -6.7	0.0 0.0	ns
t <sub>w</sub> (H) t <sub>w</sub> (L)	Pulse width, High or Low CP	6	3.0 3.0	1.5 1.0	3.0 3.0	ns
t <sub>w</sub> (L)	Pulse width, Low CLEAR	5	3.0	1.0	3.0	ns
t <sub>rec</sub>	Recovery time CLEAR to CP	5	2.0	-0.3	2.0	ns

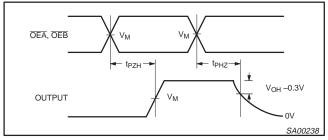
### 74ABT833

#### AC WAVEFORMS

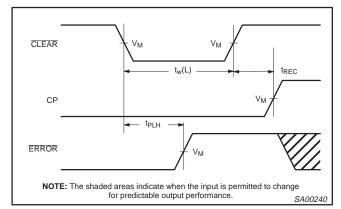
 $V_{M} = 1.5V$ ,  $V_{IN} = GND$  to 3.0V



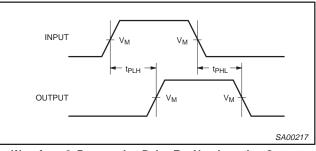
Waveform 1. Propagation Delay For Inverting Output



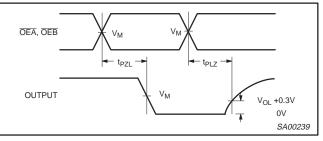
Waveform 3. 3-State Output Enable Time to High Level and Output Disable Time from High Level



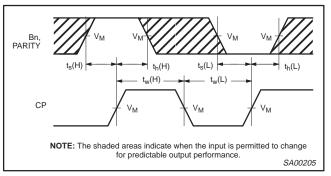
Waveform 5. CLEAR Pulse Width, CLEAR to ERROR Delay and CLEAR to Clock Recovery Time



Waveform 2. Propagation Delay For Non-Inverting Output

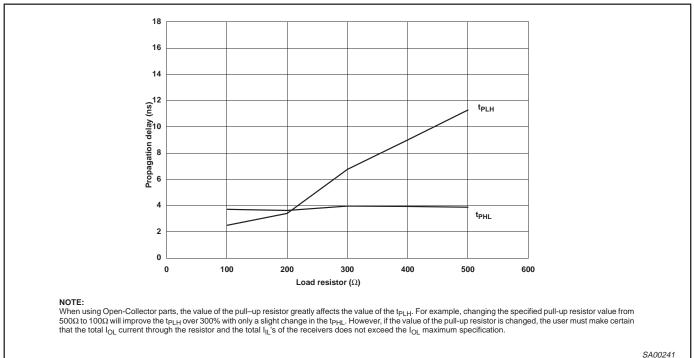


Waveform 4. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

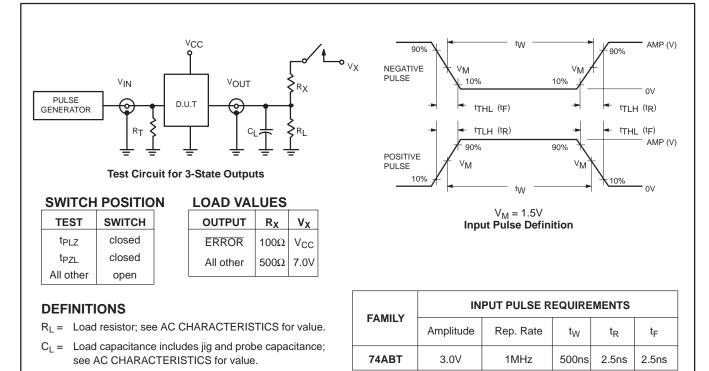


Waveform 6. Data Setup and Hold Times and Clock Pulse Width

## 74ABT833



#### TYPICAL PROPAGATION DELAYS VERSUS LOAD FOR OPEN COLLECTOR OUTPUTS



#### TEST CIRCUIT AND WAVEFORM

R<sub>T</sub> = Termination resistance should be equal to Z<sub>OUT</sub> of

pulse generators.

Product specification

# Octal transceiver with parity generator/checker (3-State)

## 74ABT833

DIP24: plastic dual in-line package; 24 leads (300 mil)	SOT222-1
SO24: plastic small outline package; 24 leads; body width 7.5 mm	SOT137-1
SSOP24: plastic shrink small outline package; 24 leads; body width 5.3 mm	SOT340-1
TSSOP24: plastic thin shrink small outline package; 24 leads; body width 4.4 mm	SOT355-1

74ABT833

NOTES

Product specification

## Octal transceiver with parity generator/checker (3-State)

## 74ABT833

DEFINITIONS		
Data Sheet Identification	Product Status	Definition
Objective Specification	Formative or in Design	This data sheet contains the design target or goal specifications for product development. Specifications may change in any manner without notice.
Preliminary Specification	Preproduction Product	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
Product Specification	Full Production	This data sheet contains Final Specifications. Philips Semiconductors reserves the right to make changes at any time without notice, in order to improve design and supply the best possible product.

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